


<b>Search Notes</b> 	<b>Application/Control No.</b> 10586292	<b>Applicant(s)/Patent Under Reexamination</b> TEY ET AL.
	<b>Examiner</b> Pablo N Tran	<b>Art Unit</b> 2618

SEARCHED			
Class	Subclass	Date	Examiner
455	347,, 300, 301, 293, 349,, 130, 191.1, 189.1, 252.1, 253.1, 311-312, 333-334, 90.3, 550.1, 575.1	2/1/10	PT
348	162	2/1/10	PT
257	686, 723, 777, 779, 659, 773, 728, 700, 702, 706, 723-724	2/1/10	PT
343	702, 772	2/1/10	PT
327	356, 359, 355, 566,	2/1/10	PT

SEARCH NOTES		
Search Notes	Date	Examiner
East/West	2/1/10	PT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
455	293, 300-301, 333, 349	2/1/10	PT
348	162	2/1/10	PT

	/P. N. T./ Primary Examiner.Art Unit 2618
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